

Modeling and Analyzing Faults to Improve Election Process Robustness

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Motivation

- Elections are more than machines
 - *A process*
- Problems arise in the process
 - Sometimes manifest as machine problems
 - Sometimes not . . .
- Plans for known and anticipated problems
 - But unexpected problems still arise

Example Problem

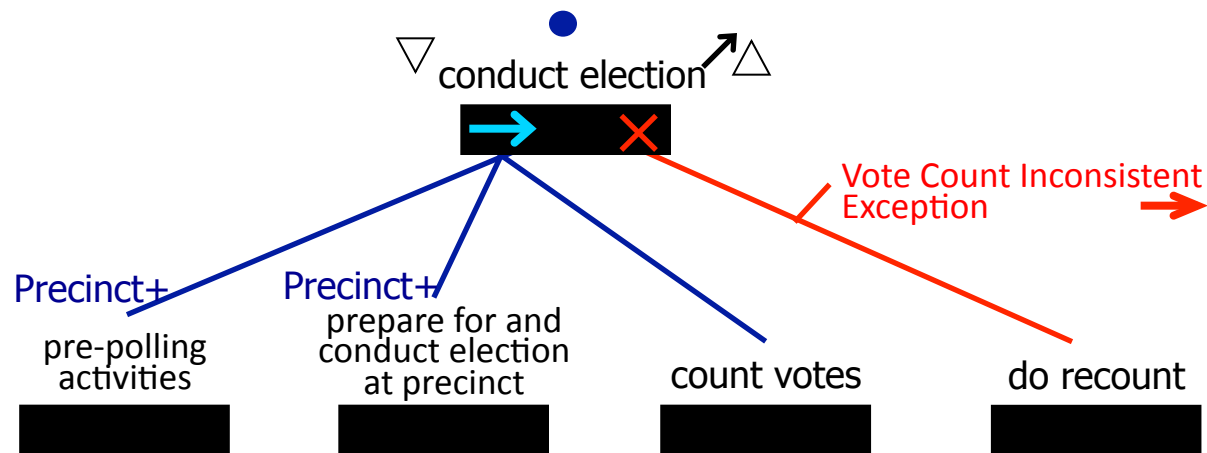
- Election procedures for validating number of ballots
 - Count them at polling station
 - Count them at Election Central
 - A discrepancy: the two ballot counts are different, or the vote counts disagree with the ballot counts
 - *What happened?*

Our Approach: *Continuous Process Improvement*

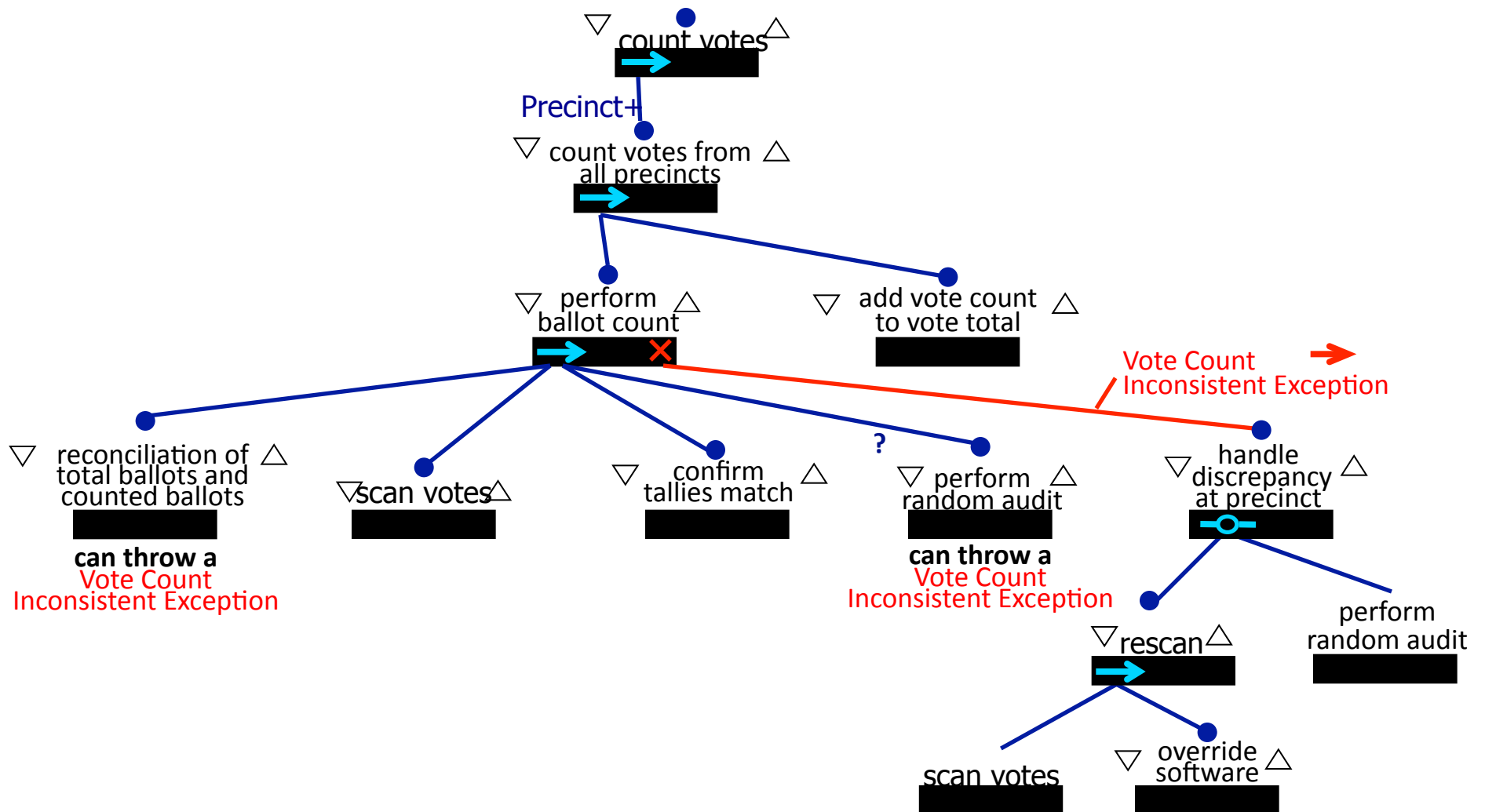
- Create a precise, accurate model of the real-world election process
- Use formal analysis methods to automatically identify potential problems in the model
 - Here, we focus on *single points of failure (SPFs)*
- Modify process model to ameliorate problems
 - Verify the modification makes things better
- Deploy improvements in real-world process
- Repeat

Election Process in Little-JIL

- Graphical process definition language with formal semantics; process represented as a hierarchical decomposition of steps



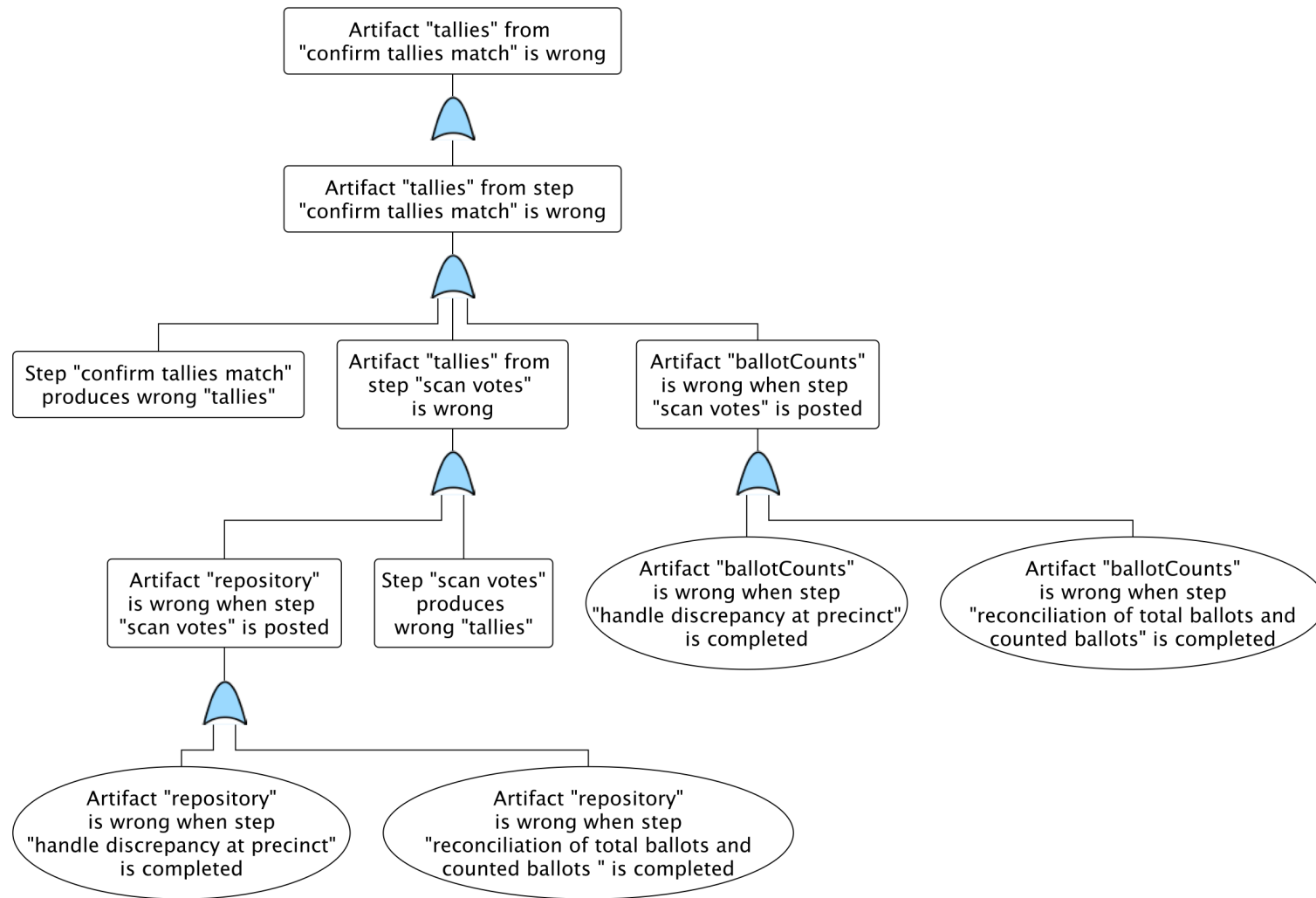
Election Process in Little-JIL (2)



Fault Tree Analysis (FTA)

- Fault trees show how problems could arise
 - Like attack trees but intent is irrelevant
- FTA can automatically generate fault trees from Little-JIL process model and a hazard
- Single Points of Failure (SPFs) can be automatically identified from fault trees

Fault Tree Generated from Model



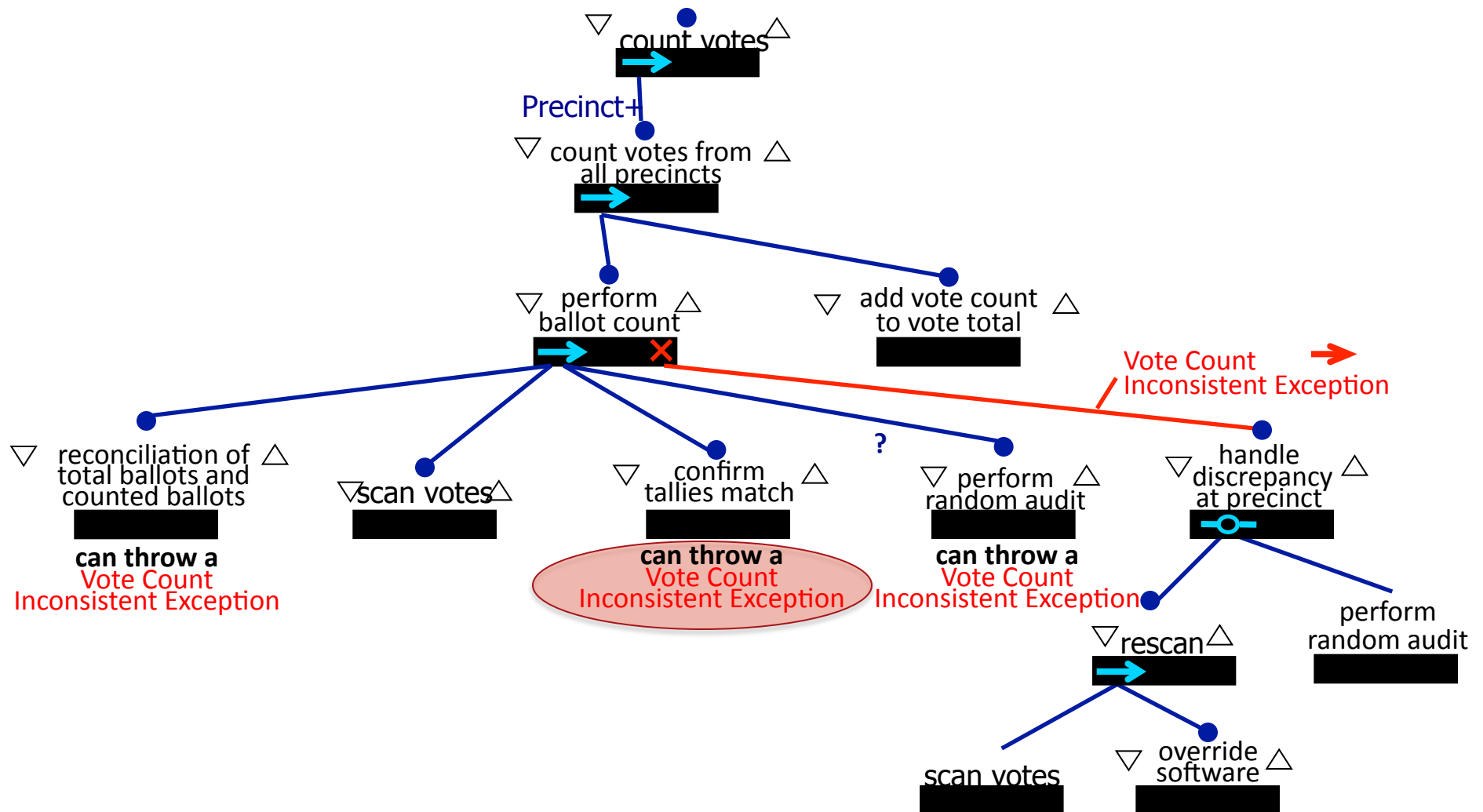
Cut Sets Computed from Fault Tree

- Combination of events such that, if all events in the cut set occur, the hazard occurs
 - *Minimal* if removal of any event causes the resulting set not to be a cut set
- Can be computed automatically from the fault tree

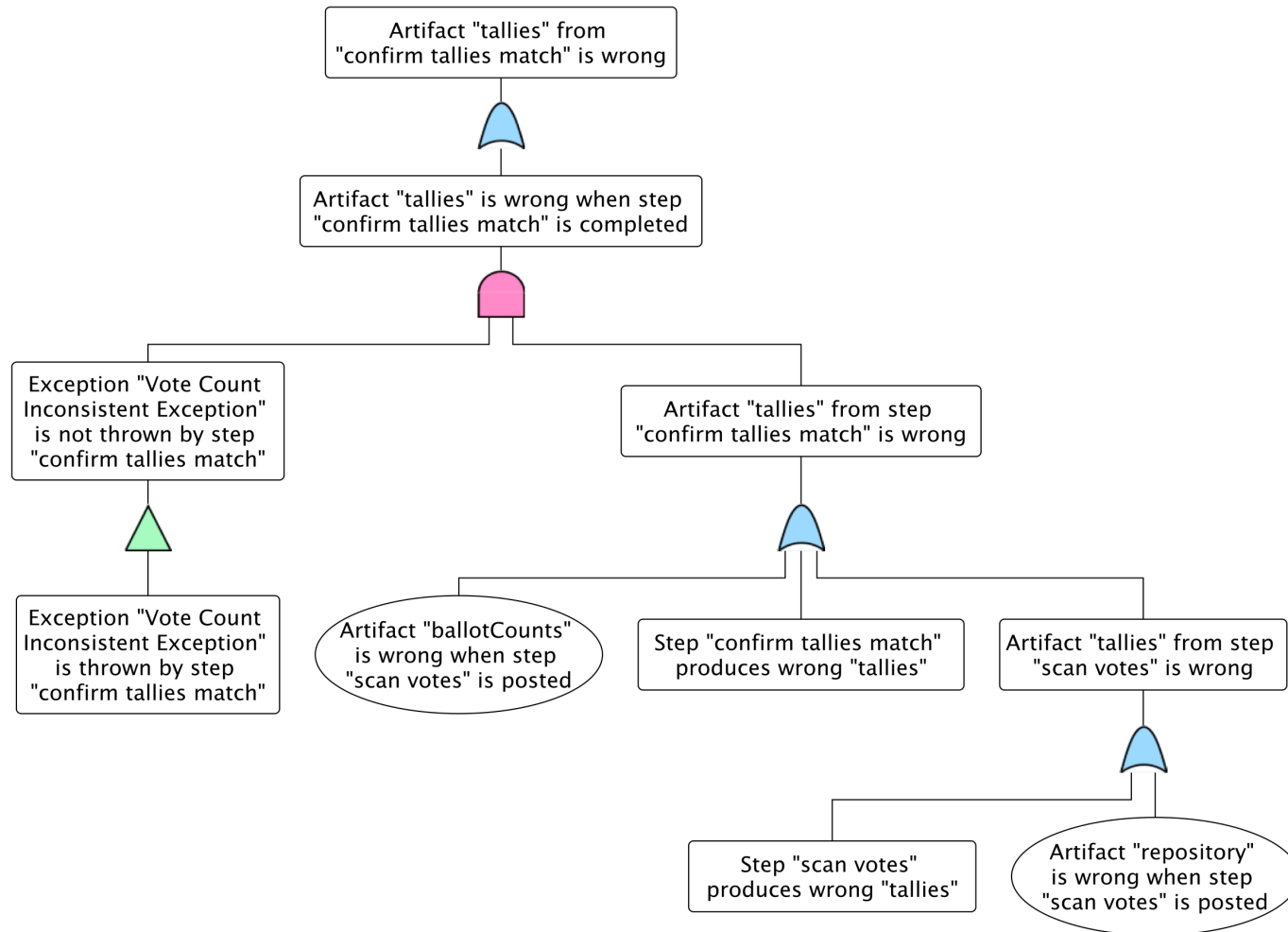
Our Original Process Model MCSs

- MCS #1 (SPF): Step **scan votes** produces **wrong tallies**
- MCS #2 (SPF): Step **confirm tallies match** produces **wrong tallies**
- Total 16 MCSs
 - 10 of size 2 or less

Add Exception Declaration to Model



And the Resulting Fault Tree



Our Revised Process Model MCSs

- MCS #1': Step **scan votes** produces **wrong tallies; Vote Count Inconsistent Exception** is NOT thrown by **step confirm tallies match**
- MCS #2': Step **confirm tallies match** produces **wrong tallies; Vote Count Inconsistent Exception** is NOT thrown by **step confirm tallies match**
- Total 16 MCSs (same as before)
 - Only 2 of size 2 or less (compared to 10 before), no SPFs

General Thoughts

- Yolo County, CA, election process modeled
 - Should work similarly for other jurisdictions
- Using fault tree analysis seems effective
 - Automatic generation of fault trees a *big* plus!
- One model covers many hazards

Conclusion

- *Continuous Process Improvement* can be successfully applied to elections
- Defects in the model can guide improvements in the real-world process
- Modifications can be evaluated in advance through formal analysis

Future Work

- Apply other forms of analysis such as Failure Mode and Effects Analysis (FMEA)
- Apply to other jurisdictions' processes
- Derive requirements for components used in the process - specifically, e-voting components
- Work with election officials to translate results into something they can use directly, i.e. without us!

Related Work

- **Direct Recording Electronic (DRE) machines**
 - Research: Compuware; UConn VoTeR Center; ACCURATE; Brennan Center for Justice; RABA; EVEREST; Caltech/MIT Voting Technology Project; Proebstel et al; Yasinsac et al
 - Statewide reports: CA, MD, OH, ...
- **Verification of Elections**
 - Mercuri & Neumann; Saltman
- **Requirements for elections**
 - Mitrou; Lambrinoudakis et al

Related Work (continued)

- Election Process Modeling
 - Election Assessment Hearing; Raunak et al; Simidchieva et al; Curtis et al; Antonyan et al; Hall et al
- Fault Tree Analysis
 - Helmer et al; Zhang et al; Rushdi, Ba-Rukab; Yee; Peisert et al; Nai Fovino et al

Thanks!

- Artifacts and full fault trees available at **<http://laser.cs.umass.edu/elections/>**
- Thanks to NSF for sponsoring work
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- Thanks to Yolo County, CA election officials, especially Tom Stanionis and Freddie Oakley